## Notice of References Cited Application/Control No. 10/810,621 Examiner Sarvesh J. Nadkarni Applicant(s)/Patent Under Reexamination LU ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,839,048	01-2005	Park, Cheol-Woo	345/102
*	В	US-6,043,797	03-2000	Clifton et al.	345/589
*	С	US-2006/0170646	08-2006	Chou et al.	345/102
*	D	US-6,987,499	01-2006	Yamaguchi et al.	345/89
*	E	US-6,894,670	05-2005	Funakoshi et al.	345/89
*	F	US-6,862,012	03-2005	Funakoshi et al.	345/88
*	G	US-6,611,249	08-2003	Evanicky et al.	345/102
*	Н	US-7,129,456	10-2006	loka et al.	250/208.1
*	١	US-7,092,008	08-2006	Bernard et al.	348/180
*	J	US-6,963,668	11-2005	Engeldrum et al.	382/233
*	К	US-6,844,881	01-2005	Chen et al.	345/589
*	L	US-7,084,881	08-2006	Chen et al.	345/589
*	М	US-6,275,207	08-2001	Nitta et al.	345/89

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
ł	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.